



HGL70R190E-W

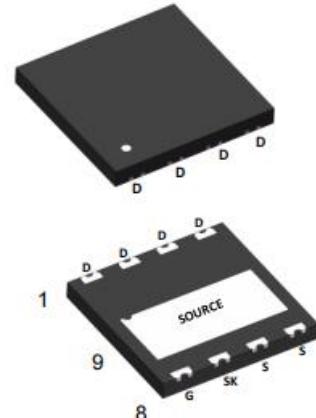
700V GaN Enhancement-mode Power Transistor

1. General description

700V GaN-on-Silicon Enhancement-mode Power Transistor in package DFN8*8

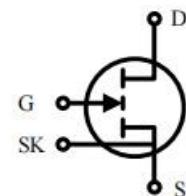
2. Features

- Enhancement mode transistor-Normally off power switch
- Ultra high switching frequency
- No reverse-recovery charge
- Low gate charge, low output charge
- Qualified for industrial applications according to JEDEC Standards
- ESD safeguard
- RoHS, Pb-free, REACH-compliant



3. Applications

- AC-DC converters
- DC-DC converters
- Totem pole PFC
- Fast battery charging
- High density power conversion
- High efficiency power conversion



4. Key performance parameters

Table 1 Key performance parameters at $T_j = 25^\circ\text{C}$

| Parameter | Value | Unit |
|---|-------|------------------|
| $V_{DS,\text{max}}$ | 700 | V |
| $R_{DS(\text{on})},\text{max} @ V_{GS} = 6\text{V}$ | 190 | $\text{m}\Omega$ |
| $Q_{G,\text{typ}} @ V_{DS} = 400\text{V}$ | 2.8 | nC |
| $I_{D,\text{pulse}}$ | 20.5 | A |
| $Q_{OSS} @ V_{DS} = 400\text{V}$ | 24.5 | nC |
| $Q_{rr} @ V_{DS} = 400\text{V}$ | 0 | nC |

5. Pin information

Table 2 Pin information

| Gate | Drain | Kelvin Source | Source |
|------|---------|---------------|--------|
| 8 | 1,2,3,4 | 7 | 5,6,9 |

Table 3 Ordering information

| Type/Ordering Code | Package | Product Code |
|--------------------|---------|--------------|
| HGL70R190E-W | DFN8*8 | HGL70R190E-W |



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6. Maximum ratings

at $T_j = 25^\circ\text{C}$ unless otherwise specified.

Exceeding the maximum ratings may destroy the device. For further information, contact Huake sales office.

Table 4 Maximum ratings

| Parameter | Symbol | Values | Unit | Note/Test Condition |
|--|----------------------------|-------------|------|--|
| Drain source voltage | $V_{DS,\text{max}}$ | 700 | V | $V_{GS} = 0 \text{ V}$, $T_j = -55^\circ\text{C} \text{ to } 150^\circ\text{C}$ |
| Drain source voltage transient ¹ | $V_{DS(\text{transient})}$ | 800 | V | $V_{GS} = 0 \text{ V}$ |
| Drain source voltage, pulsed ² | $V_{DS,\text{pulse}}$ | 750 | V | $T_j = 25^\circ\text{C}$; total time < 10h |
| Drain source voltage, pulsed ² | $V_{DS,\text{pulse}}$ | 750 | V | $T_j = 125^\circ\text{C}$; total time < 1h |
| Continuous current, drain source | I_D | 11.5 | A | $T_c = 25^\circ\text{C}$ |
| Pulsed current, drain source ³ | $I_{D,\text{pulse}}$ | 20.5 | A | $T_c = 25^\circ\text{C}; V_G = 6 \text{ V}$; $t_{PULSE} = 10\mu\text{s}$ |
| Pulsed current, drain source ³ | $I_{D,\text{pulse}}$ | 11.5 | A | $T_c = 125^\circ\text{C}; V_G = 6 \text{ V}$; $t_{PULSE} = 10\mu\text{s}$ |
| Gate source voltage, continuous ⁴ | V_{GS} | -1.4 to +7 | V | $T_j = -55^\circ\text{C} \text{ to } 150^\circ\text{C}$ |
| Gate source voltage, pulsed | $V_{GS,\text{pulse}}$ | -20 to +10 | V | $T_j = -55^\circ\text{C} \text{ to } 150^\circ\text{C}$; $t_{PULSE} = 50 \text{ ns}$, $f = 100 \text{ kHz}$ open drain |
| Power dissipation | P_{tot} | 83 | W | $T_c = 25^\circ\text{C}$ |
| Operating temperature | T_j | -55 to +150 | °C | |
| Storage temperature | T_{stg} | -55 to +150 | °C | |

1 $V_{DS(\text{transient})}$ is intended for non-repetitive events, $t_{PULSE} < 200 \mu\text{s}$

2 $V_{DS,\text{pulse}}$ is intended for repetitive pulse, $t_{PULSE} < 100 \text{ ns}$

3 Limit was extracted from characterization test, not measured during production

4 The minimum V_{GS} is clamped by ESD protection circuit, as shown in Figure 10

7. Thermal characteristics

Table 5 Thermal characteristics

| Parameter | Symbol | Values | Unit | Note/Test Condition |
|--------------------------------------|-------------------|--------|------|---------------------|
| Thermal resistance, junction-case | R_{thJC} | 1.49 | °C/W | |
| Maximum reflow soldering temperature | T_{sold} | 260 | °C | MSL3 |

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8. Electric characteristics

at $T_j = 25^\circ\text{C}$, unless specified otherwise**Table 6 Static characteristics**

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|----------------------------------|---------------------|--------|------|------|------------------|---|
| | | Min. | Typ. | Max. | | |
| Gate threshold voltage | $V_{GS(\text{th})}$ | 1.2 | 1.7 | 2.5 | V | $I_D=12.2\text{mA}; V_{DS}=V_{GS}; T_j=25^\circ\text{C}$ |
| | | -- | 1.7 | -- | | $I_D=12.2\text{mA}; V_{DS}=V_{GS}; T_j=150^\circ\text{C}$ |
| Drain-source leakage current | I_{DSS} | -- | 0.45 | 20 | μA | $V_{DS}=700\text{V}; V_{GS}=0\text{V}; T_j=25^\circ\text{C}$ |
| | | -- | 6 | -- | | $V_{DS}=700\text{V}; V_{GS}=0\text{V}; T_j=150^\circ\text{C}$ |
| Gate-source leakage current | I_{GSS} | -- | 60 | -- | μA | $V_{GS}=6\text{V}; V_{DS}=0\text{V}$ |
| Drain-source on-state resistance | $R_{DS(\text{on})}$ | -- | 138 | 190 | $\text{m}\Omega$ | $V_{GS}=6\text{V}; I_D=3.9\text{A}; T_j=25^\circ\text{C}$ |
| | | -- | 300 | -- | | $V_{GS}=6\text{V}; I_D=3.9\text{A}; T_j=150^\circ\text{C}$ |
| Gate resistance | R_G | -- | 5.8 | -- | Ω | $f=5\text{MHz}; \text{open drain}$ |

Table 7 Dynamic characteristics

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|---|--------------|--------|------|------|------|--|
| | | Min. | Typ. | Max. | | |
| Input capacitance | C_{iss} | -- | 96 | -- | pF | $V_{GS}=0\text{V}; V_{DS}=400\text{V}; f=100\text{kHz}$ |
| Output capacitance | C_{oss} | -- | 30 | -- | pF | $V_{GS}=0\text{V}; V_{DS}=400\text{V}; f=100\text{kHz}$ |
| Reverse transfer capacitance | C_{rss} | -- | 0.5 | -- | pF | $V_{GS}=0\text{V}; V_{DS}=400\text{V}; f=100\text{kHz}$ |
| Effective output capacitance, energy related ¹ | $C_{o(er)}$ | -- | 43 | -- | pF | $V_{GS}=0\text{V}; V_{DS}=0 \text{ to } 400\text{V}$ |
| Effective output capacitance, time related ² | $C_{o(tr)}$ | -- | 60 | -- | pF | $V_{GS}=0\text{V}; V_{DS}=0 \text{ to } 400\text{V}$ |
| Output charge | Q_{oss} | -- | 24.5 | -- | nC | $V_{GS}=0\text{V}; V_{DS}=0 \text{ to } 400\text{V}$ |
| Turn-on delay time | $t_{d(on)}$ | -- | 1.4 | -- | ns | $V_{DS}=400\text{V}; I_D=8\text{A}; L=318\text{\mu H}; V_{GS}=6\text{V}; R_{on}=10\Omega; R_{off}=2\Omega;$ See Figure 22 |
| Turn-off delay time | $t_{d(off)}$ | -- | 1.7 | -- | ns | |
| Rise time | t_r | -- | 4 | -- | ns | |
| Fall time | t_f | -- | 4 | -- | ns | |

¹ $C_{o(er)}$ is the fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400 V² $C_{o(tr)}$ is the fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400 V



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Table 8 Gate charge characteristics

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|----------------------|------------|--------|------|------|------|---|
| | | Min. | Typ. | Max. | | |
| Gate charge | Q_G | -- | 2.8 | -- | nC | $V_{GS} = 0$ to 6 V; $V_{DS} = 400$ V; $I_D = 3.9$ A |
| Gate-source charge | Q_{GS} | -- | 0.25 | -- | nC | |
| Gate-drain charge | Q_{GD} | -- | 1.1 | -- | nC | |
| Gate Plateau Voltage | V_{Plat} | -- | 2.2 | -- | V | |

Table 9 Reverse conduction characteristics

| Parameter | Symbol | Values | | | Unit | Note/Test Condition |
|-------------------------------|---------------|--------|------|------|------|-------------------------------------|
| | | Min. | Typ. | Max. | | |
| Source-Drain reverse voltage | V_{SD} | -- | 2.6 | -- | V | $V_{GS} = 0$ V; $I_{SD} = 3.9$ A |
| Pulsed current, reverse | $I_{S,pulse}$ | -- | -- | 20.5 | A | $V_{GS} = 6$ V; $t_{PULSE}=10\mu s$ |
| Reverse recovery charge | Q_{rr} | -- | 0 | -- | nC | $I_{SD}=3.9$ A; $V_{DS} = 400$ V |
| Reverse recovery time | t_{rr} | -- | 0 | -- | ns | |
| Peak reverse recovery current | I_{rrm} | -- | 0 | -- | A | |

9. Electric characteristics diagrams

at $T_j = 25^\circ\text{C}$, unless specified otherwise

Figure 1 Typ. output characteristics

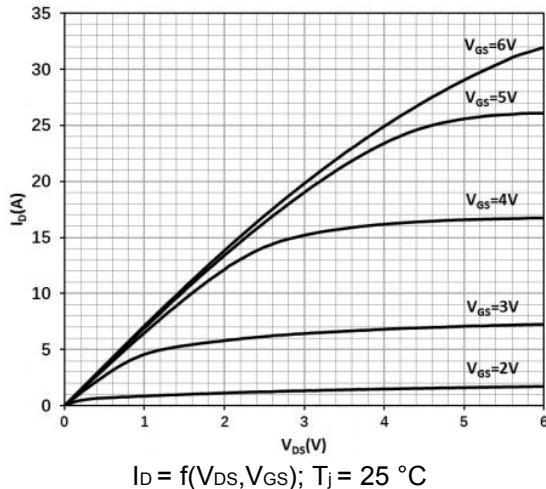


Figure 3 Typ. Drain-source on-state resistance

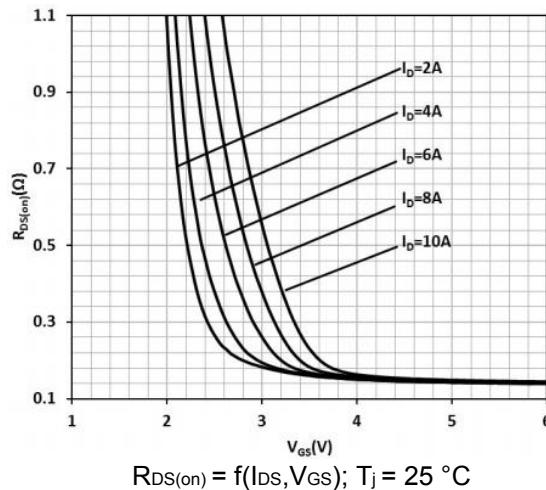


Figure 5 Typ. channel reverse characteristics

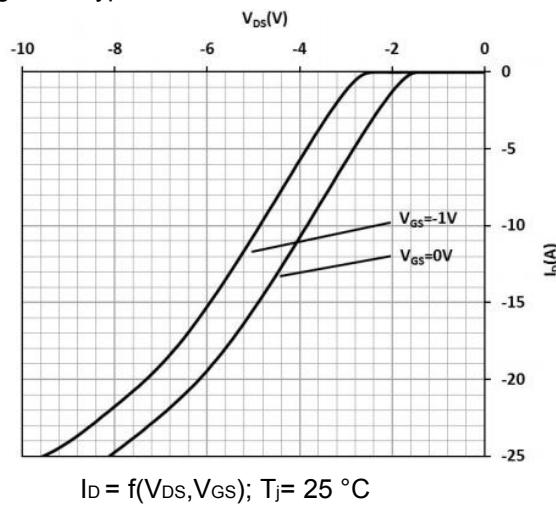


Figure 2 Typ. output characteristics

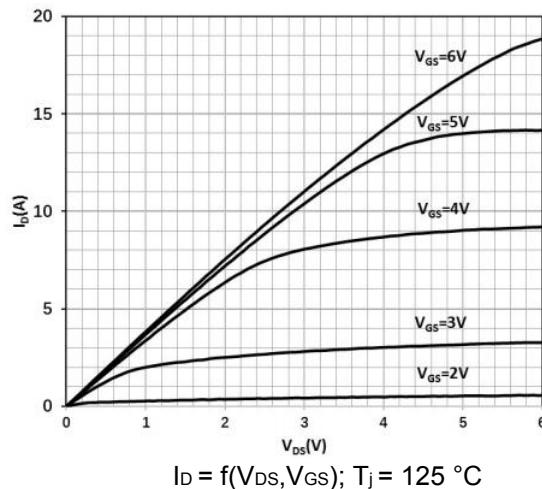


Figure 4 Typ. Drain-source on-state resistance

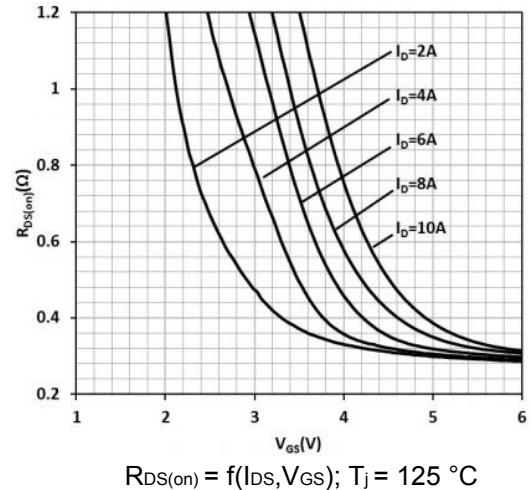
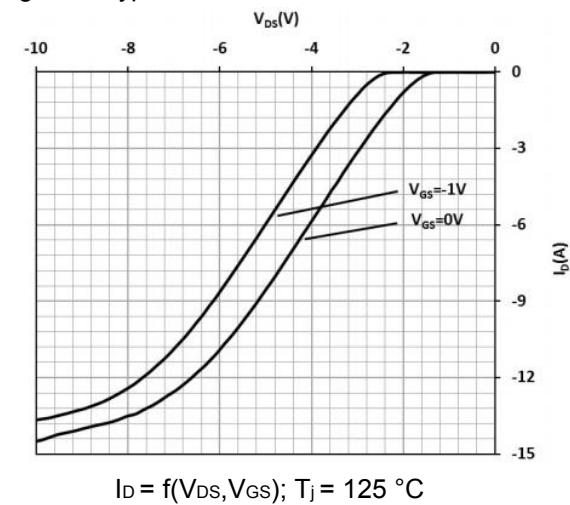


Figure 6 Typ. channel reverse characteristics

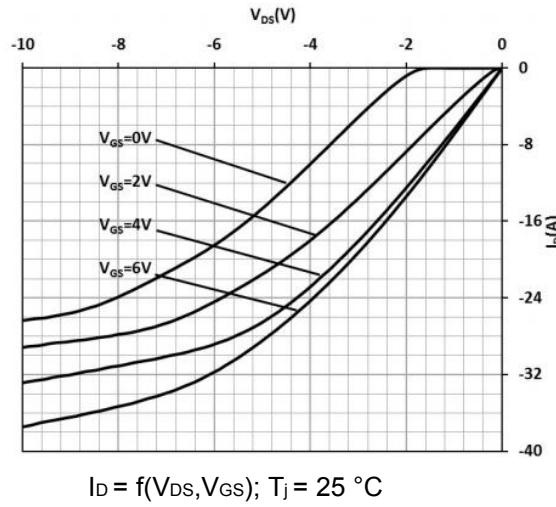




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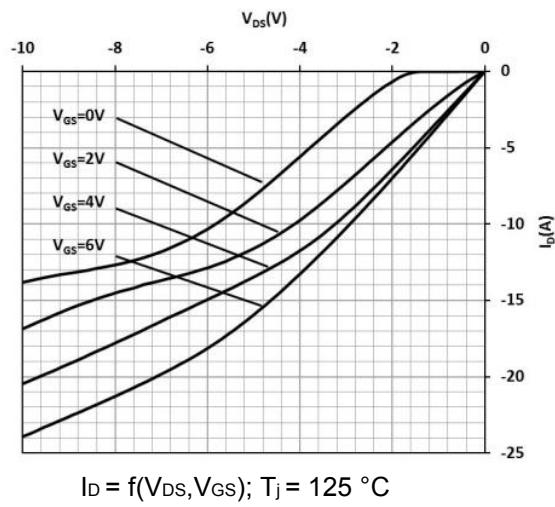
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Figure 7 Typ. channel reverse characteristics



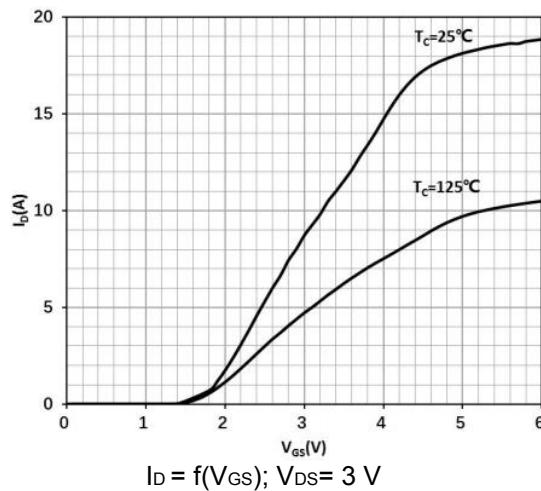
$$I_D = f(V_{DS}, V_{GS}); T_j = 25 \text{ } ^\circ\text{C}$$

Figure 8 Typ. channel reverse characteristics



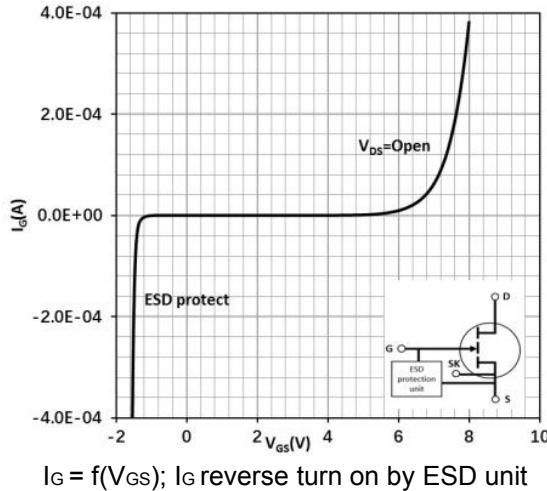
$$I_D = f(V_{DS}, V_{GS}); T_j = 125 \text{ } ^\circ\text{C}$$

Figure 9 Typ. transfer characteristics



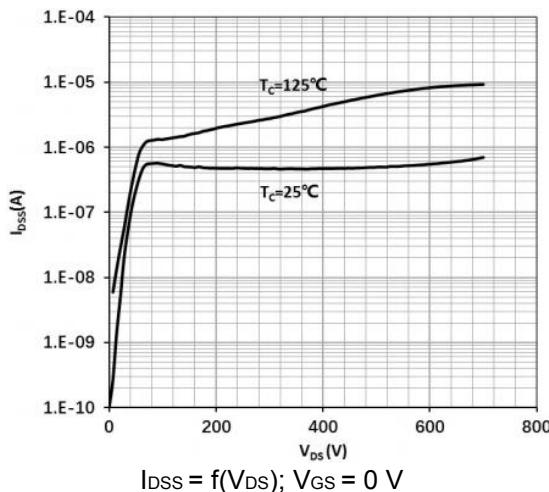
$$I_D = f(V_{GS}); V_{DS} = 3 \text{ V}$$

Figure 10 Typ. Gate-to-Source leakage



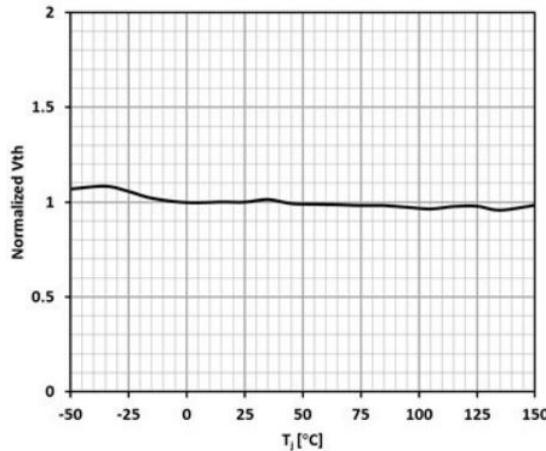
$$I_G = f(V_{GS}); I_G \text{ reverse turn on by ESD unit}$$

Figure 11 Drain-source leakage characteristics



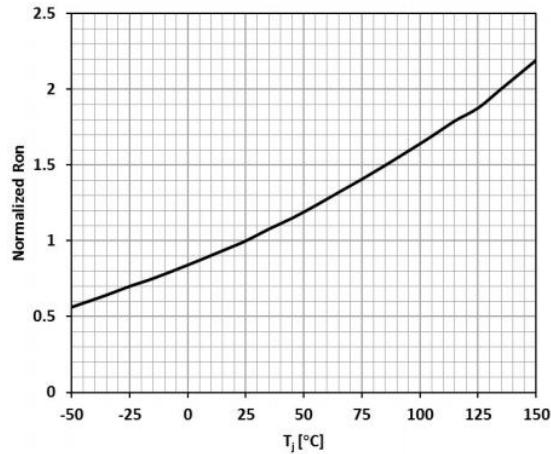
$$I_{DSS} = f(V_{DS}); V_{GS} = 0 \text{ V}$$

Figure 12 Gate threshold voltage



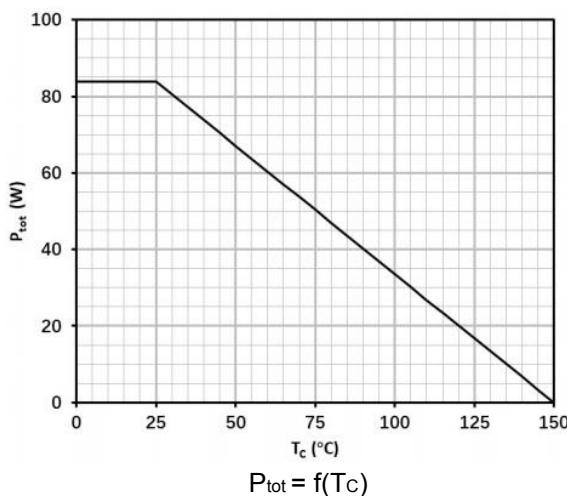
$V_{TH} = f(T_j)$; $V_{GS} = V_{DS}$; $I_D = 12.2$ mA

Figure 13 Drain-source on-state resistance



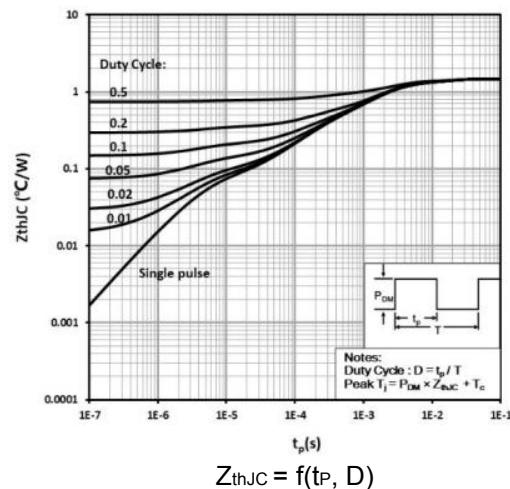
$R_{DS(on)} = f(T_j)$; $I_D = 3.9$ A; $V_G=6$ V

Figure 14 Power dissipation



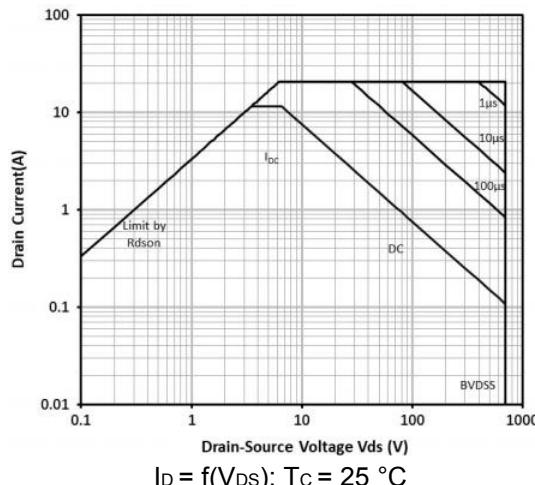
$P_{tot} = f(T_c)$

Figure 15 Max.transient thermal impedance



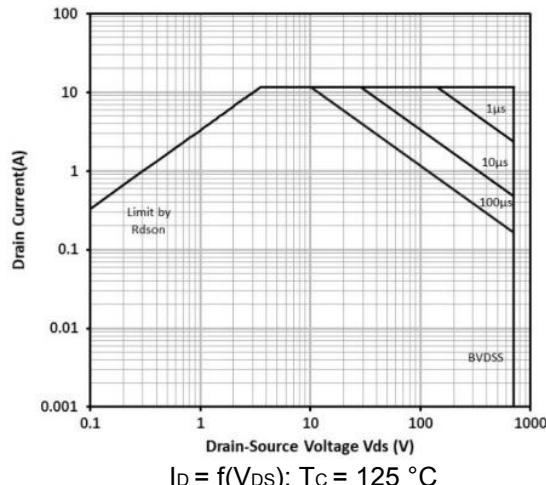
$Z_{thJC} = f(t_p, D)$

Figure 16 Safe operating area



$I_D = f(V_{DS})$; $T_c = 25$ °C

Figure 17 Safe operating area



$I_D = f(V_{DS})$; $T_c = 125$ °C

Figure 18 Typ. gate charge

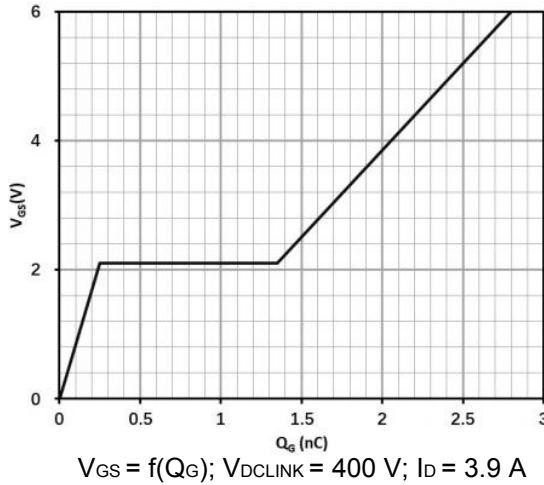


Figure 19 Typ. capacitances

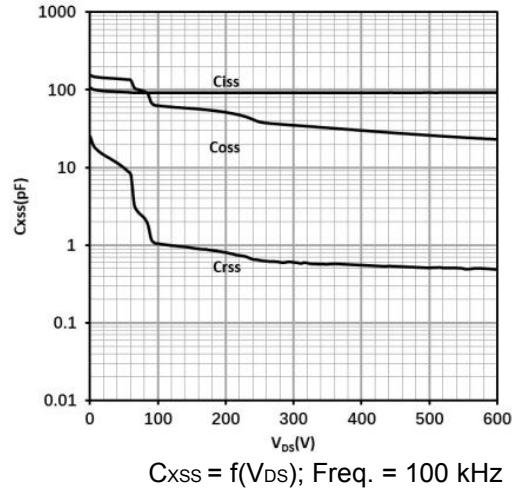


Figure 20 Typ. output charge

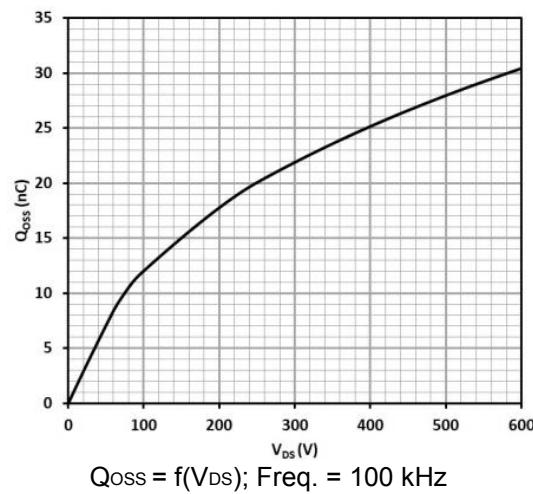


Figure 21 Typ. Coss stored Energy

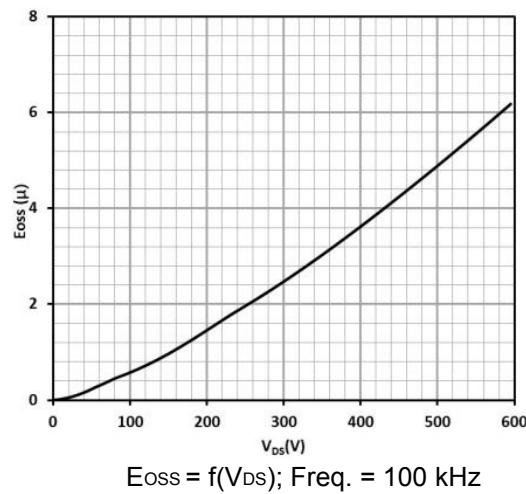
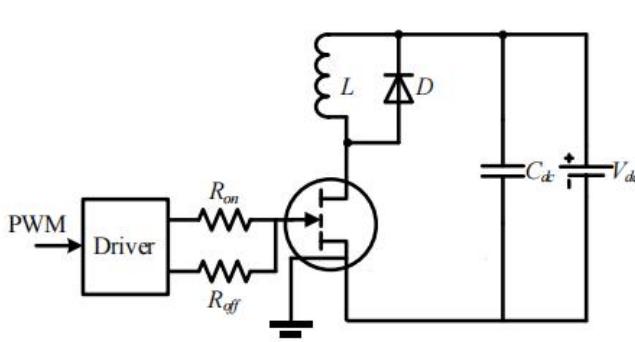
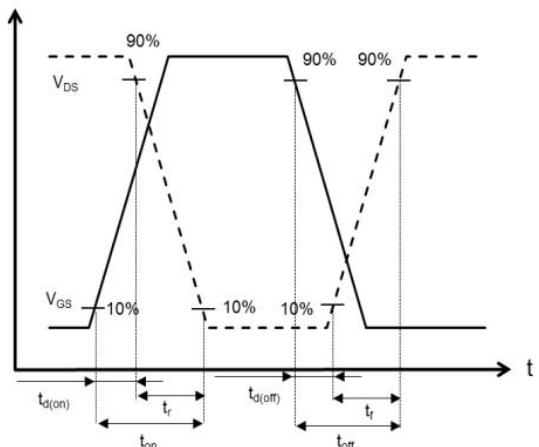


Figure 22 Typ. Switching times with inductive load



$V_{DS}=400\text{ V}, I_D=8\text{ A}, L=318\text{ }\mu\text{H}, V_{GS}=6\text{ V}, R_{on}=10\Omega, R_{off}=2\Omega$

Figure 23 Typ. Switching times waveform



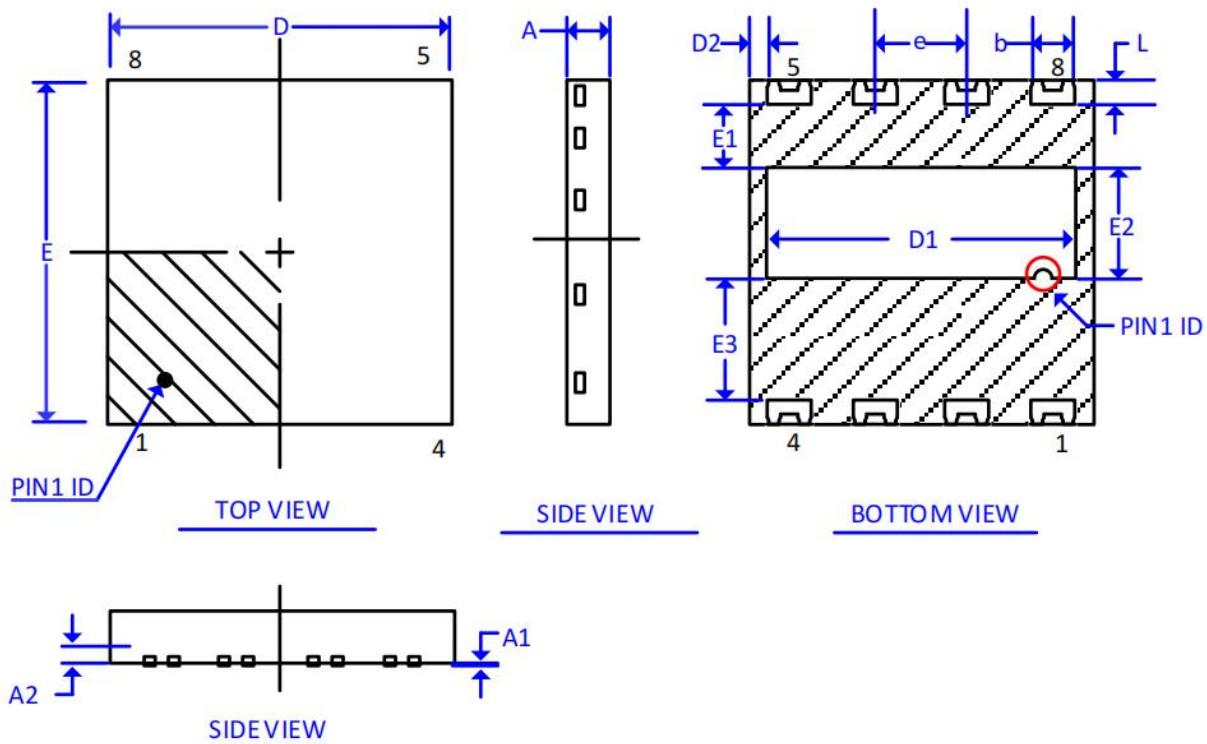


10.Package outlines

DFN8*8-8L Package Dimensions

UNIT: mm

| symbol | min | nom | max | symbol | min | nom | max |
|--------|------|-----------|------|--------|------|-----------|------|
| A | 0.80 | 0.90 | 1.00 | E | | 8.00B.S.C | |
| A1 | 0.00 | 0.02 | 0.05 | E1 | 0.90 | 1.00 | 1.10 |
| A2 | -- | 0.203ref | -- | E2 | 3.10 | 3.20 | 3.30 |
| b | 0.92 | 1.00 | 1.05 | E3 | 2.70 | 2.80 | 2.90 |
| D | | 8.00B.S.C | | e | | 2.00B.S.C | |
| D1 | 6.84 | 6.94 | 7.04 | L | 0.40 | 0.50 | 0.60 |
| D2 | 0.40 | 0.50 | 0.60 | | | | |

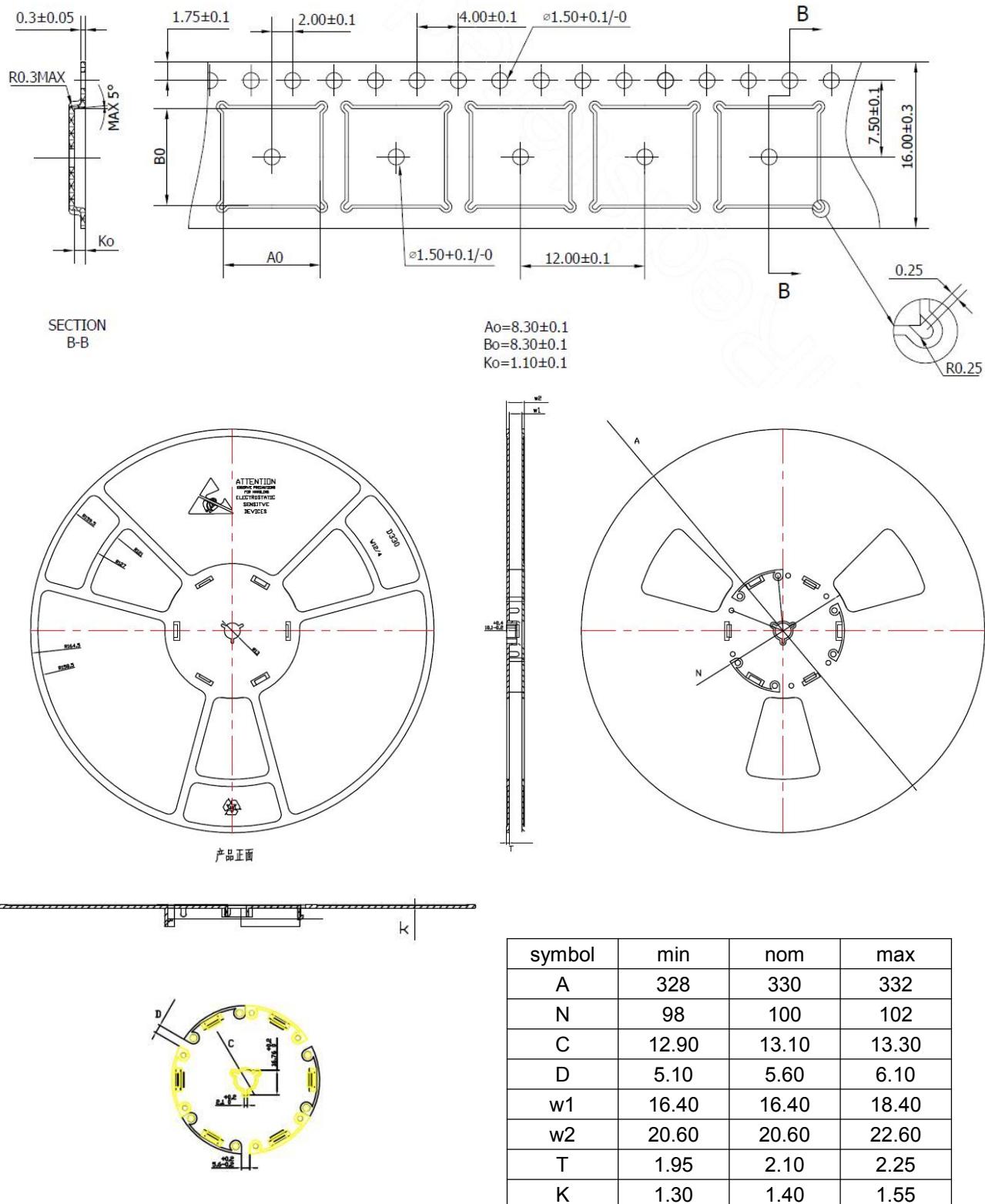




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11.Reel Information





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Important Notice

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版本履历表：

| 序号 | 版本号 | 修改时间 | 修改记录 |
|----|------|-----------|------|
| 1 | V1.0 | 2023-3-21 | 首次发行 |
| | | | |